

**FDS8840NZ****N-Channel PowerTrench[®] MOSFET****40 V, 18.6 A, 4.5 mΩ****Features**

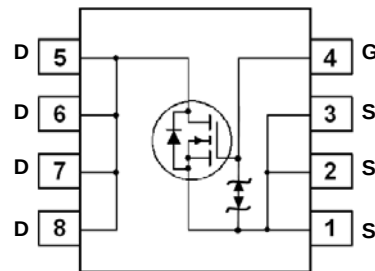
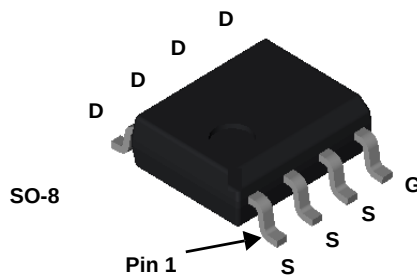
- Max $r_{DS(on)}$ = 4.5 mΩ at $V_{GS} = 10\text{ V}$, $I_D = 18.6\text{ A}$
- Max $r_{DS(on)}$ = 6.0 mΩ at $V_{GS} = 4.5\text{ V}$, $I_D = 14.9\text{ A}$
- HBM ESD protection level of 6 kV typical(note 3)
- High performance trench technology for extremely low $r_{DS(on)}$ and fast switching
- High power and current handling capability
- Termination is Lead-free and RoHS Compliant

**General Description**

The FDS8840NZ has been designed to minimize losses in power conversion application. Advancements in both silicon and package technologies have been combined to offer the lowest $r_{DS(on)}$ while maintaining excellent switching performance.

Applications

- Synchronous Buck for Vcore and Server
- Notebook Battery Pack
- Load Switch



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MOSFET Maximum Ratings $T_A = 25\text{ }^{\circ}\text{C}$ unless otherwise noted

Symbol	Parameter	Ratings	Units
V_{DS}	Drain to Source Voltage	40	V
V_{GS}	Gate to Source Voltage	± 20	V
I_D	Drain Current -Continuous	18.6	A
	-Pulsed	63	
E_{AS}	Single Pulse Avalanche Energy (Note 4)	600	mJ
P_D	Power Dissipation $T_A = 25\text{ }^{\circ}\text{C}$ (Note 1a)	2.5	W
	Power Dissipation $T_A = 25\text{ }^{\circ}\text{C}$ (Note 1b)	1.0	
T_J, T_{STG}	Operating and Storage Junction Temperature Range	-55 to +150	$^{\circ}\text{C}$

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case (Note 1)	25	$^{\circ}\text{C/W}$
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	50	

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDS8840NZ	FDS8840NZ	SO8	13 "	12 mm	2500 units

Electrical Characteristics $T_J = 25\text{ }^{\circ}\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
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Off Characteristics

BV_{DSS}	Drain to Source Breakdown Voltage	$I_D = 250\text{ }\mu\text{A}$, $V_{GS} = 0\text{ V}$	40			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\text{ }\mu\text{A}$, referenced to $25\text{ }^{\circ}\text{C}$		31		mV/ $^{\circ}\text{C}$
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 32\text{ V}$, $V_{GS} = 0\text{ V}$			1	μA
I_{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20\text{ V}$, $V_{DS} = 0\text{ V}$			± 10	μA

On Characteristics

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = 250\text{ }\mu\text{A}$	1.0	1.8	3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250\text{ }\mu\text{A}$, referenced to $25\text{ }^{\circ}\text{C}$		-6		mV/ $^{\circ}\text{C}$
$r_{DS(on)}$	Static Drain to Source On Resistance	$V_{GS} = 10\text{ V}$, $I_D = 18.6\text{ A}$		3.9	4.5	m Ω
		$V_{GS} = 4.5\text{ V}$, $I_D = 14.9\text{ A}$		4.6	6.0	
		$V_{GS} = 10\text{ V}$, $I_D = 18.6\text{ A}$, $T_J = 125\text{ }^{\circ}\text{C}$		5.9	7.0	
g_{FS}	Forward Transconductance	$V_{DS} = 5\text{ V}$, $I_D = 18.6\text{ A}$		83		S

Dynamic Characteristics

C_{iss}	Input Capacitance	$V_{DS} = 20\text{ V}$, $V_{GS} = 0\text{ V}$, $f = 1\text{ MHz}$		5665	7535	pF
C_{oss}	Output Capacitance			650	865	pF
C_{rss}	Reverse Transfer Capacitance			445	670	pF
R_g	Gate Resistance			1.2		Ω

Switching Characteristics

$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 20\text{ V}$, $I_D = 18.6\text{ A}$, $V_{GS} = 10\text{ V}$, $R_{GEN} = 6\text{ }\Omega$		18	32	ns
t_r	Rise Time			13	23	ns
$t_{d(off)}$	Turn-Off Delay Time			57	103	ns
t_f	Fall Time			11	20	ns
Q_g	Total Gate Charge	$V_{GS} = 0\text{ V}$ to 10 V	$V_{DD} = 20\text{ V}$, $I_D = 18.6\text{ A}$	103	144	nC
Q_g	Total Gate Charge	$V_{GS} = 0\text{ V}$ to 5 V		54	76	nC
Q_{gs}	Gate to Source Charge			16		nC
Q_{gd}	Gate to Drain "Miller" Charge			19		nC

Drain-Source Diode Characteristics

V_{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0\text{ V}$, $I_S = 18.6\text{ A}$		0.8	1.2	V
		$V_{GS} = 0\text{ V}$, $I_S = 2.1\text{ A}$		0.7	1.2	
t_{rr}	Reverse Recovery Time	$I_F = 18.6\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$		33	53	ns
Q_{rr}	Reverse Recovery Charge			21	34	nC

NOTES:

1. $R_{\theta JA}$ is determined with the device mounted on a 1 in^2 pad 2 oz copper pad on a $1.5 \times 1.5\text{ in.}$ board of FR-4 material. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a) $50\text{ }^{\circ}\text{C/W}$ when mounted on a 1 in^2 pad of 2 oz copper.



b) $125\text{ }^{\circ}\text{C/W}$ when mounted on a minimum pad.

2. Pulse Test: Pulse Width $< 300\text{ }\mu\text{s}$, Duty cycle $< 2.0\%$.

3. The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

4. Starting $T_J = 25\text{ }^{\circ}\text{C}$, $L = 3\text{ mH}$, $I_{AS} = 20\text{ A}$, $V_{DD} = 40\text{ V}$, $V_{GS} = 10\text{ V}$.

Typical Characteristics $T_J = 25^\circ\text{C}$ unless otherwise noted

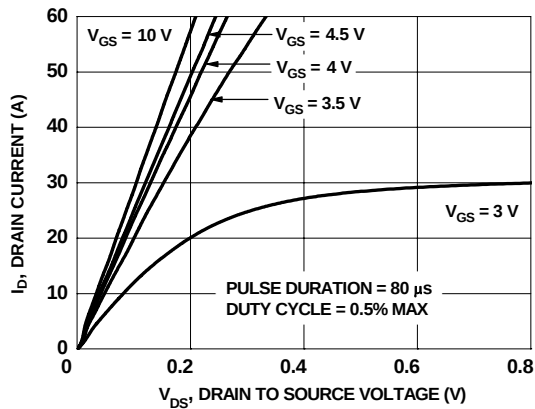


Figure 1. On-Region Characteristics

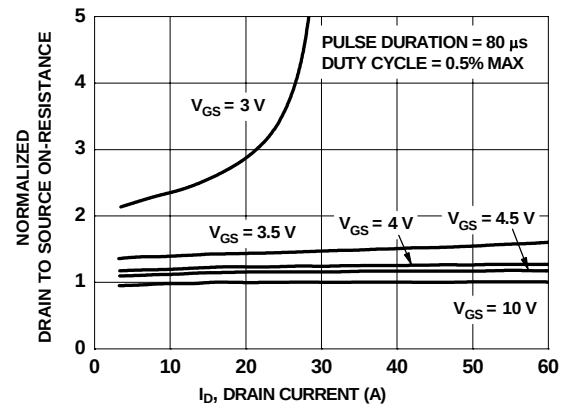


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

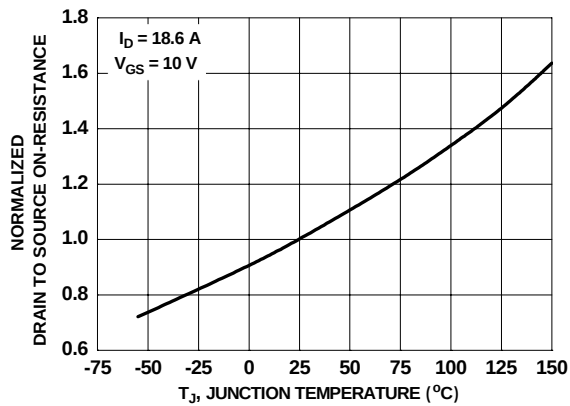


Figure 3. Normalized On-Resistance vs Junction Temperature

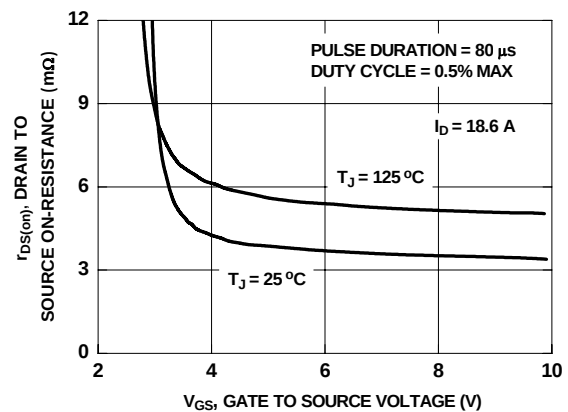


Figure 4. On-Resistance vs Gate to Source Voltage

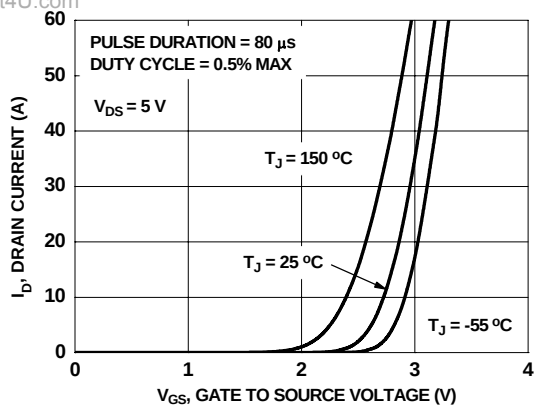


Figure 5. Transfer Characteristics

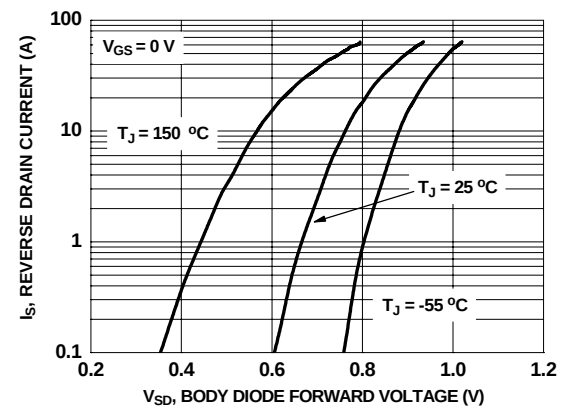


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics $T_J = 25^\circ\text{C}$ unless otherwise noted

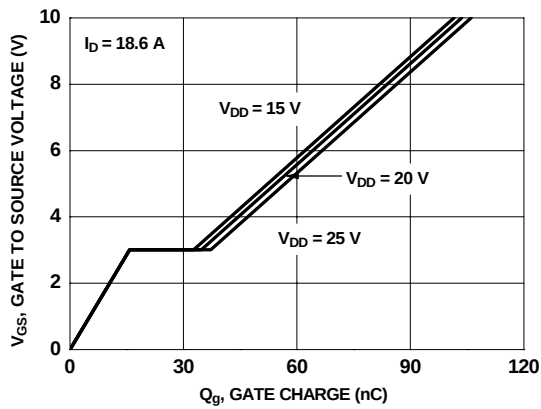


Figure 7. Gate Charge Characteristics

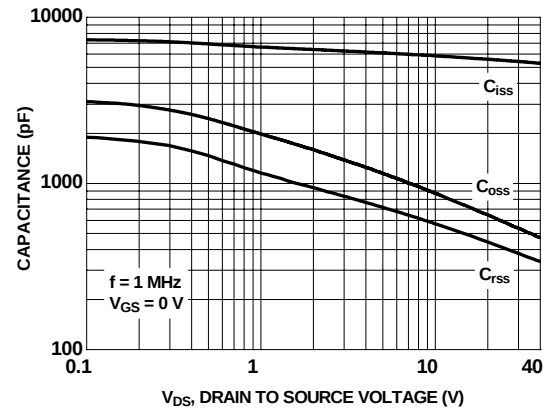


Figure 8. Capacitance vs Drain to Source Voltage

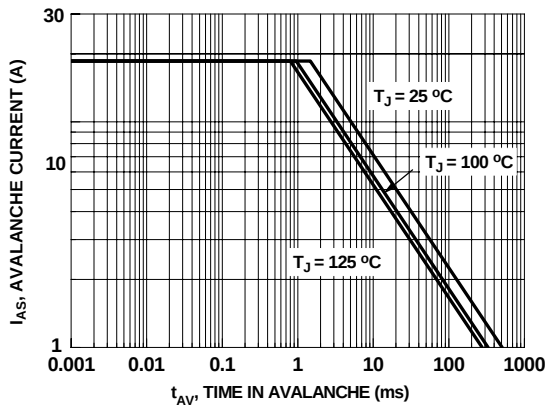


Figure 9. Unclamped Inductive Switching Capability

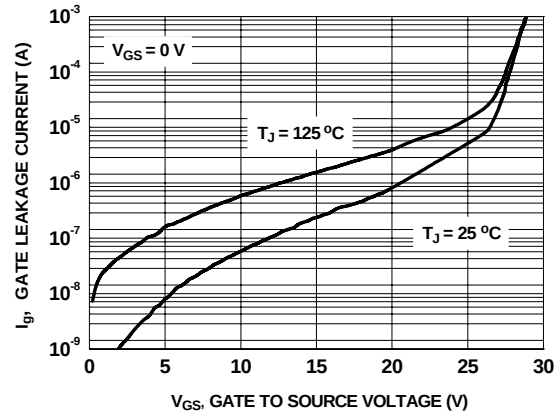
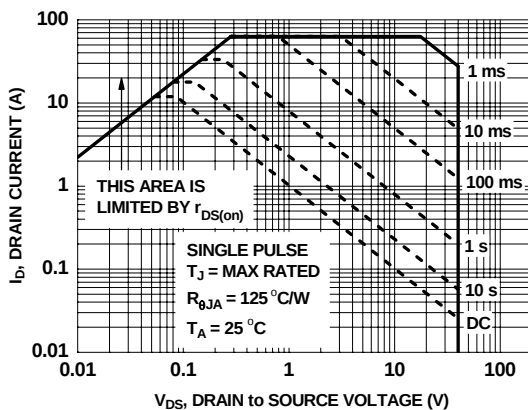
Figure 10. I_{gss} vs V_{GS} 

Figure 11. Forward Bias Safe Operating Area

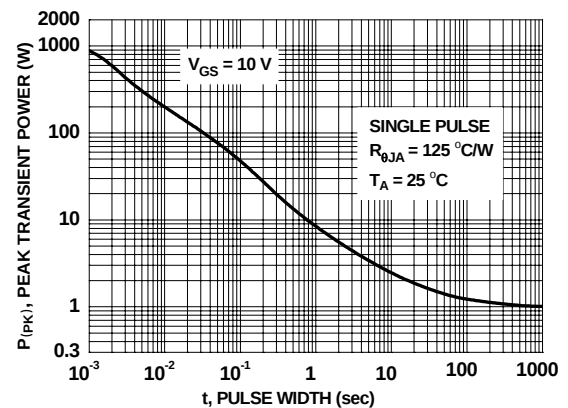
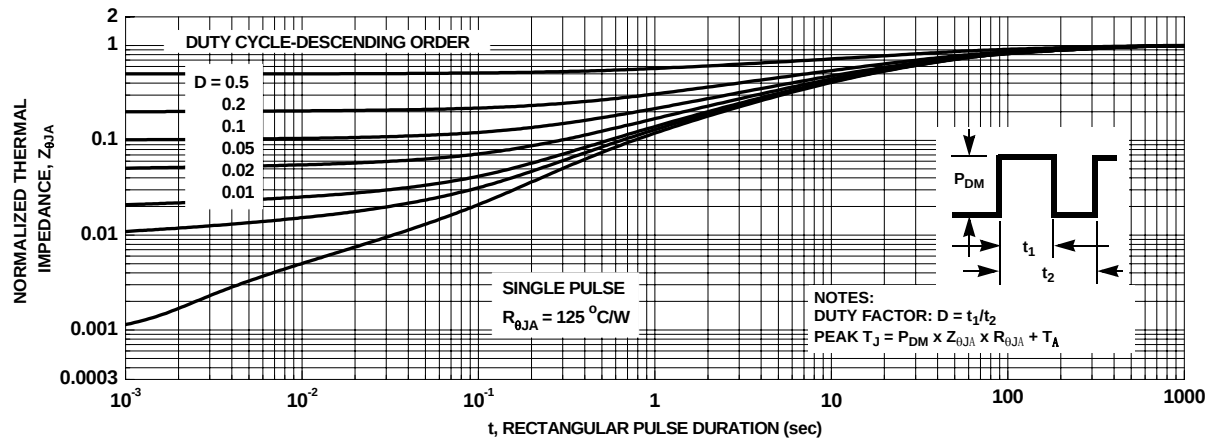


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics $T_J = 25\text{ }^{\circ}\text{C}$ unless otherwise noted





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